# ES52F3D20N-18.414M



### ES52F3 D 20 N -18.414M

Operating Temperature Range -30°C to +75°C

Frequency Stability ±2.0ppm Maximum

,	- Nominal Frequency
	18.414MHz

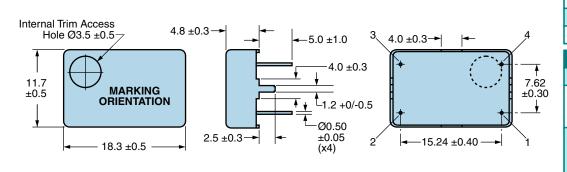
Control Voltage None (No Connect on Pin 1)

ELECTRICAL SPECIFICATIONS		
Nominal Frequency	18.414MHz	
Frequency Stability	±2.0ppm Maximum (Inclusive of Operating Temperature Range)	
Frequency Stability vs. Input Voltage	±0.3ppm Maximum (±5%)	
Aging at 25°C	±1ppm/Year Maximum	
Frequency Stability vs. Load	±0.2ppm Maximum (±2pF)	
Operating Temperature Range	-30°C to +75°C	
Supply Voltage	3.3Vdc ±5%	
Input Current	1.5mA Maximum	
Output Voltage	0.7Vp-p Minimum	
Load Drive Capability	10kOhms//10pF	
Output Logic Type	Clipped Sinewave	
Control Voltage	None (No Connect on Pin 1)	
Internal Trim	±3ppm Minimum (Top of Can)	
Modulation Bandwidth	10kHz Minimum (Measured at -3dB with a Control Voltage of 1.65Vdc)	
Input Impedance	10kOhms Typical	
Phase Noise	-70dBc at 10Hz Offset, -100dBc at 100Hz Offset, -130dBc at 1kHz Offset, -140dBc at 10kHz Offset, - 145dBc at 100kHz Offset	
Storage Temperature Range	-40°C to +85°C	
ENVIRONMENTAL & MECHANICAL SPECIFICATIONS		
Fine Leak Test	MIL-STD-883, Method 1014 Condition A (Internal Crystal Only)	
Gross Leak Test	MIL-STD-883, Method 1014 Condition C (Internal Crystal Only)	
Lead Integrity	MIL-STD-883, Method 2004	
Mechanical Shock	MIL-STD-202, Method 213 Condition C	
Resistance to Soldering Heat	MIL-STD-202, Method 210	
Resistance to Solvents	MIL-STD-202, Method 215	
Solderability	MIL-STD-883, Method 2003	
Temperature Cycling	MIL-STD-883, Method 1010	
Vibration	MIL-STD-883, Method 2007 Condition A	



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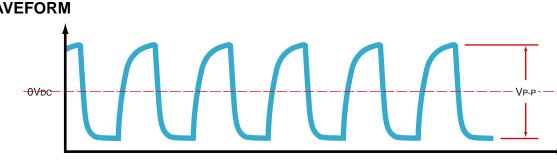
## **MECHANICAL DIMENSIONS (all dimensions in millimeters)**



PIN	CONNECTION
1	No Connect
2	Case/Ground
3	Output
4	Supply Voltage
LINE	MARKING
1	ECLIPTEK
2	<b>18.414M</b> <i>M</i> =Nominal Frequency Unit of Measure
3	XXYZZ XX=Ecliptek Manufacturing Code Y=Last Digit of the Year ZZ=Week of the Year

**OUTPUT WAVEFORM** 

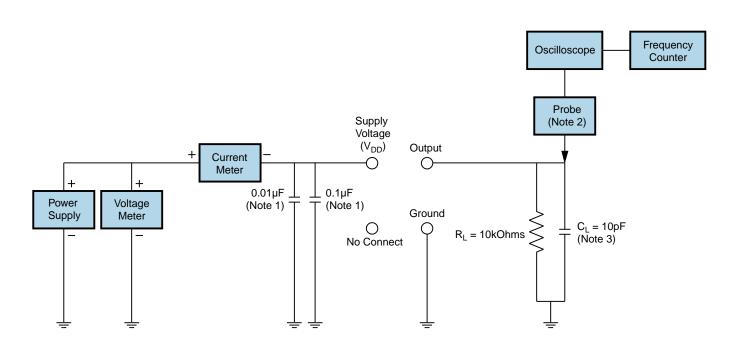
CLOCK OUTPUT



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### **Test Circuit for No Connect Option**



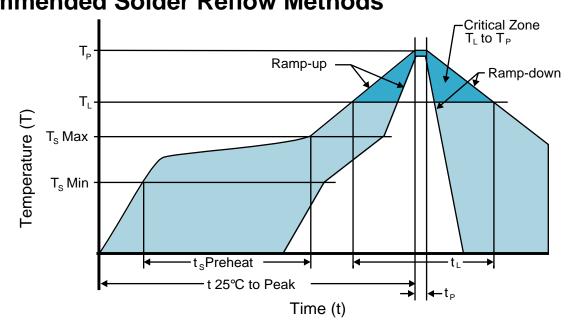
Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V<sub>DD</sub> pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value  $\dot{C}_{L}$  includes sum of all probe and fixture capacitance.



# ES52F3D20N-18.414M Recommended Solder Reflow Methods



### Low Temperature Solder Bath (Wave Solder)

5°C/second Maximum
N/A
150°C
N/A
30 - 60 Seconds
5°C/second Maximum
150°C
200 Seconds Maximum
245°C Maximum
245°C Maximum 1 Time / 235°C Maximum 2 Times
5 seconds Maximum 1 Time / 15 seconds Maximum 2 Times
5°C/second Maximum
N/A
Level 1

### Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

### **High Temperature Manual Soldering**

260°C Maximum for 5 seconds Maximum, 2 times Maximum.

### Low Temperature Solder Bath (Wave Solder) Note 1

Device is non-hermetic; Post reflow aqueous wash is not recommended

### Low Temperature Solder Bath (Wave Solder) Note 2

Temperatures shown are applied to back of PCB board and device leads only.